

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$[(\text{max. power of channel, including tune-up tolerance, mW})/(\text{min. test separation distance, mm})] \cdot [\sqrt{f(\text{GHz})}] \leq 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- $f(\text{GHz})$ is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

Modulation	Channel Freq. (GHz)	Conduct ed power (dBm)	Conducte d power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
GFSK	2.402	2.8	1.91	3±1	4	2.51	<5	0.77860	3.00	YES
	2.441	3.49	2.23	3±1	4	2.51	<5	0.78490	3.00	YES
	2.480	3.27	2.12	3±1	4	2.51	<5	0.79114	3.00	YES
$\pi/4$ -DQPSK	2.402	3.7	2.34	4±1	5	3.16	<5	0.98020	3.00	YES
	2.441	4.18	2.62	4±1	5	3.16	<5	0.98813	3.00	YES
	2.480	4	2.51	4±1	5	3.16	<5	0.99599	3.00	YES
8-DQPSK	2.402	4.03	2.53	4±1	5	3.16	<5	0.98020	3.00	YES
	2.441	4.5	2.82	4±1	5	3.16	<5	0.98813	3.00	YES
	2.480	4.3	2.69	4±1	5	3.16	<5	0.99599	3.00	YES
BLE-1M	2.402	4.89	3.08	5±1	6	3.98	<5	1.23400	3.00	YES
	2.440	5.18	3.30	5±1	6	3.98	<5	1.24373	3.00	YES
	2.480	4.85	3.05	5±1	6	3.98	<5	1.25388	3.00	YES
BLE-2M	2.402	4.96	3.13	5±1	6	3.98	<5	1.23400	3.00	YES
	2.440	5.27	3.37	5±1	6	3.98	<5	1.24373	3.00	YES
	2.480	4.98	3.15	5±1	6	3.98	<5	1.25388	3.00	YES

Conclusion:

For the max result : $1.25388 \leq 3.0$ for 1g SAR, SAR is not required.



Signature:

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